

**Search Notes**

Application/Control No.

10/817,279

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

MEANEY ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	2,7,18	11/29/2006	PK
370	203	11/29/2006	PK
710	33,36	11/29/2006	PK
709	238	11/29/2006	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) Updated and new search --USPAT, USPGPUB Class/sub searched: 716/1-18 (see attached)	11/29/2006	PK
--USPAT, USPGPUB (Continue) Cks/sub searched: 370/203-211; 710/33-42; 709/238-240, 201-203, 213-216 (see attached)	11/29/2006	PK
New search --EPO, JPO, IBM TDB, Derwent (see attached)l	11/29/2006	PK
EE/IEEE Xplore New Search (see attached)	11/29/2006	PK